Corrigendum

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The authors regret that their paper, ‘Characterization and dielectric properties of vacuum-deposited zinc phthalocyanine thin film’ (Kaur M, Kumar R, Dogra R, Arora N and Sharma N (2018), *Surface*

Innovations 6(1–2): 63–70, <https://doi.org/10.1680/jsuin.17.00042>), contains errors in the data of Figures 7, 8, 9 and 10 and Table 4. The corrected Figures and Table are provided below.

Figure 7. Variation in capacitance with frequency of ZnPc films at bias voltage

Figure 9. Variation of ΔB at different frequency range for ZnPc films at bias voltage

Figure 8. Variation in dielectric constant with frequency of ZnPc films at bias voltage

Figure 10. Variation in AC conductivity with frequency of ZnPc films at bias voltage

Table 4. AC electrical parameters for ZnPc films

Applied bias voltage: V	ΔB maxima: Hz	Relaxation time: s	Mobility: $\text{m}^2/(\text{V s})$
1	15 348	6.5×10^{-5}	4.38×10^{-9}
3	14 015	7.1×10^{-5}	1.33×10^{-9}
5	13 660	7.3×10^{-5}	7.81×10^{-10}

The following line of the Conclusion (p. 69) is also amended as follows

The hole mobility and relaxation time have been determined and found to lie in the range $7.81 \times 10^{-10} - 4.38 \times 10^{-9} \text{ m}^2/(\text{V s})$ and $7.32 \times 10^{-5} - 6.52 \times 10^{-5} \text{ s}$, respectively.

The authors sincerely apologise for the errors and any inconvenience caused.